NXP USA Inc. - <u>MPC8358CZUADDE Datasheet</u>





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Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	266MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	740-LBGA
Supplier Device Package	740-TBGA (37.5x37.5)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8358czuadde

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



- Eight TDM interfaces on the MPC8360E and four TDM interfaces on the MPC8358E with 1-bit mode for E3/T3 rates in clear channel
- Sixteen independent baud rate generators and 30 input clock pins for supplying clocks to UCC and MCC serial channels (MCC is only available on the MPC8360E)
- Four independent 16-bit timers that can be interconnected as four 32-bit timers
- Interworking functionality:
 - Layer 2 10/100-Base T Ethernet switch
 - ATM-to-ATM switching (AAL0, 2, 5)
 - Ethernet-to-ATM switching with L3/L4 support
 - PPP interworking
- Security engine is optimized to handle all the algorithms associated with IPSec, SSL/TLS, SRTP, 802.11i®, iSCSI, and IKE processing. The security engine contains four crypto-channels, a controller, and a set of crypto execution units (EUs).
 - Public key execution unit (PKEU) supporting the following:
 - RSA and Diffie-Hellman
 - Programmable field size up to 2048 bits
 - Elliptic curve cryptography
 - F2m and F(p) modes
 - Programmable field size up to 511 bits
 - Data encryption standard execution unit (DEU)
 - DES, 3DES
 - Two key (K1, K2) or three key (K1, K2, K3)
 - ECB and CBC modes for both DES and 3DES
 - Advanced encryption standard unit (AESU)
 - Implements the Rinjdael symmetric key cipher
 - Key lengths of 128, 192, and 256 bits, two key
 - ECB, CBC, CCM, and counter modes
 - ARC four execution unit (AFEU)
 - Implements a stream cipher compatible with the RC4 algorithm
 - 40- to 128-bit programmable key
 - Message digest execution unit (MDEU)
 - SHA with 160-, 224-, or 256-bit message digest
 - MD5 with 128-bit message digest
 - HMAC with either SHA or MD5 algorithm
 - Random number generator (RNG)
 - Four crypto-channels, each supporting multi-command descriptor chains
 - Static and/or dynamic assignment of crypto-execution units via an integrated controller
 - Buffer size of 256 bytes for each execution unit, with flow control for large data sizes
 - Storage/NAS XOR parity generation accelerator for RAID applications
- Dual DDR SDRAM memory controllers on the MPC8360E and a single DDR SDRAM memory controller on the MPC8358E
 - Programmable timing supporting both DDR1 and DDR2 SDRAM
 - On the MPC8360E, the DDR buses can be configured as two 32-bit buses or one 64-bit bus; on the MPC8358E, the DDR bus can be configured as a 32- or 64-bit bus
 - 32- or 64-bit data interface, up to 333 MHz (for the MPC8360E) and 266 MHz (for the MPC8358E) data rate
 - Four banks of memory, each up to 1 Gbyte



Power Sequencing

This table shows the estimated typical I/O power dissipation for the device.

Interface	Parameter	GV _{DD} (1.8 V)	GV _{DD} (2.5 V)	OV _{DD} (3.3 V)	LV _{DD} (3.3 V)	LV _{DD} (2.5 V)	Unit	Comments
DDR I/O	200 MHz, 1 \times 32 bits	0.3	0.46	_	_	—	W	—
$R_s = 20 \Omega$	200 MHz, 1 \times 64 bits	0.4	0.58		_	—	W	—
$R_t = 50 \Omega$	200 MHz, 2×32 bits	0.6	0.92	_	_	—	W	_
	266 MHz, 1 \times 32 bits	0.35	0.56	_	_	—	W	_
	266 MHz, 1 \times 64 bits	0.46	0.7	_	_	—	W	_
	266 MHz, 2×32 bits	0.7	1.11		—	—	W	_
	333 MHz, 1 \times 32 bits	0.4	0.65	_	_	—	W	_
	333 MHz, 1 \times 64 bits	0.53	0.82		—	—	W	_
	333 MHz, 2×32 bits	0.81	1.3		—	—	W	_
Local Bus I/O	133 MHz, 32 bits	—	—	0.22	_	_	W	_
3 pairs of clocks	83 MHz, 32 bits	—	—	0.14	—	—	W	—
	66 MHz, 32 bits	—	—	0.12	—	—	W	_
	50 MHz, 32 bits	—	—	0.09	—	—	W	_
PCI I/O	33 MHz, 32 bits	—	—	0.05	—	—	W	_
Load = 30 pF	66 MHz, 32 bits	—	—	0.07	—	—	W	—
10/100/1000	MII or RMII	—	—	_	0.01	—	W	Multiply by
Load = 20 pF	GMII or TBI	—	—	_	0.04	—	W	interfaces used.
	RGMII or RTBI	—	—	—	—	0.04	W	
Other I/O	_	—	_	0.1	—	—	W	—

Table 6. Estimated Typical I/O Power Dissipation

4 Clock Input Timing

This section provides the clock input DC and AC electrical characteristics for the MPC8360E/58E.

NOTE

The rise/fall time on QUICC Engine block input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of V_{DD} ; fall time refers to transitions from 90% to 10% of V_{DD} .



QUICC Engine Block Operating Frequency Limitations

5.3 QUICC Engine Block Operating Frequency Limitations

This section specify the limits of the AC electrical characteristics for the operation of the QUICC Engine block's communication interfaces.

NOTE

The settings listed below are required for correct hardware interface operation. Each protocol by itself requires a minimal QUICC Engine block operating frequency setting for meeting the performance target. Because the performance is a complex function of all the QUICC Engine block settings, the user should make use of the QUICC Engine block performance utility tool provided by Freescale to validate their system.

This table lists the maximal QUICC Engine block I/O frequencies and the minimal QUICC Engine block core frequency for each interface.

Interface	Interface Operating Frequency (MHz)	Max Interface Bit Rate (Mbps)	Min QUICC Engine Operating Frequency ¹ (MHz)	Notes
Ethernet Management: MDC/MDIO	10 (max)	10	20	_
MII	25 (typ)	100	50	_
RMII	50 (typ)	100	50	_
GMII/RGMII/TBI/RTBI	125 (typ)	1000	250	_
SPI (master/slave)	10 (max)	10	20	_
UCC through TDM	50 (max)	70	8 imes F	2
MCC	25 (max)	16.67	16 × F	2, 4
UTOPIA L2	50 (max)	800	$2 \times F$	2
POS-PHY L2	50 (max)	800	$2 \times F$	2
HDLC bus	10 (max)	10	20	_
HDLC/transparent	50 (max)	50	8/3 × F	2, 3
UART/async HDLC	3.68 (max internal ref clock)	115 (Kbps)	20	_
BISYNC	2 (max)	2	20	
USB	48 (ref clock)	12	96	_

Table 13. QUICC Engine Block Operating Frequency Limitations

Notes:

1. The QUICC Engine module needs to run at a frequency higher than or equal to what is listed in this table.

2. 'F' is the actual interface operating frequency.\

3. The bit rate limit is independent of the data bus width (that is, the same for serial, nibble, or octal interfaces).

4. TDM in high-speed mode for serial data interface.

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR and DDR2 SDRAM interface of the MPC8360E/58E.



Table 21. DDR and DDR2 SDRAM Output AC Timing Specifications for Source Synchronous Mode (continued)

At recommended operating conditions with GV_{DD} of (1.8 V or 2.5 V) ± 5%.

Parameter ⁸	Symbol ¹	Min	Мах	Unit	Notes
MDQS epilogue end	t _{DDKHME}	-0.6	0.9	ns	7

Notes:

- The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state) for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
 </sub>
- 2. All MCK/ \overline{MCK} referenced measurements are made from the crossing of the two signals ±0.1 V.
- In the source synchronous mode, MCK/MCK can be shifted in ¼ applied cycle increments through the clock control register. For the skew measurements referenced for t_{AOSKEW} it is assumed that the clock adjustment is set to align the address/command valid with the rising edge of MCK.
- ADDR/CMD includes all DDR SDRAM output signals except MCK/MCK, MCS, and MDQ/MECC/MDM/MDQS. For the ADDR/CMD setup and hold specifications, it is assumed that the clock control register is set to adjust the memory clocks by ½ applied cycle.
- 5. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK(n) clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. In source synchronous mode, this is typically set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these two parameters have been set to the same adjustment value. Refer MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual for a description and understanding of the timing modifications enabled by use of these bits.
- Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the device.
- All outputs are referenced to the rising edge of MCK(n) at the pins of the device. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
- 8. AC timing values are based on the DDR data rate, which is twice the DDR memory bus frequency.
- 9. In rev. 2.0 silicon, t_{DDKHMH} maximum meets the specification of 0.6 ns. In rev. 2.0 silicon, due to errata, t_{DDKHMH} minimum is –0.9 ns. Refer to Errata DDR18 in *Chip Errata for the MPC8360E, Rev. 1*.

This figure shows the DDR SDRAM output timing for address skew with respect to any MCK.







GMII, MII, RMII, TBI, RGMII, and RTBI AC Timing Specifications

Physical Layer Device Specification Version 1.2a (9/22/2000). The electrical characteristics for the MDIO and MDC are specified in Section 8.3, "Ethernet Management Interface Electrical Characteristics."

8.1.1 10/100/1000 Ethernet DC Electrical Characteristics

The electrical characteristics specified here apply to media independent interface (MII), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), reduced media independent interface (RMII) signals, management data input/output (MDIO) and management data clock (MDC).

The MII and RMII interfaces are defined for 3.3 V, while the RGMII and RTBI interfaces can be operated at 2.5 V. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3*. The RMII interface follows the *RMII Consortium RMII Specification Version 1.2*.

Table 25. RGMII/RTBI, GMII, TBI, MII, and RMII DC Electrical Characteristics (when operating at 3.3 V)

Parameter	Symbol	Conditions		Min	Мах	Unit	Notes
Supply voltage 3.3 V	LV _{DD}	_		2.97	3.63	V	1
Output high voltage	V _{OH}	I _{OH} = -4.0 mA	$LV_{DD} = Min$	2.40	LV _{DD} + 0.3	V	—
Output low voltage	V _{OL}	I _{OL} = 4.0 mA	$LV_{DD} = Min$	GND	0.50	V	—
Input high voltage	V _{IH}	—	_	2.0	LV _{DD} + 0.3	V	—
Input low voltage	V _{IL}	—	_	-0.3	0.90	V	—
Input current	I _{IN}	0 V ≤V _{IN} ≤LV _{DD}		—	±10	μA	—

Note:

1. GMII/MII pins that are not needed for RGMII, RMII, or RTBI operation are powered by the OV_{DD} supply.

Table 26. RGMII/RTBI DC Electrical Characteristics	(when o	perating	at 2.5 V)
	·······			,

Parameters	Symbol	Conditions		Min	Max	Unit
Supply voltage 2.5 V	LV _{DD}	—		2.37	2.63	V
Output high voltage	V _{OH}	I _{OH} = -1.0 mA	LV _{DD} = Min	2.00	LV _{DD} + 0.3	V
Output low voltage	V _{OL}	I _{OL} = 1.0 mA	$LV_{DD} = Min$	GND – 0.3	0.40	V
Input high voltage	V _{IH}	—	LV _{DD} = Min	1.7	LV _{DD} + 0.3	V
Input low voltage	V _{IL}	—	LV _{DD} = Min	-0.3	0.70	V
Input current	I _{IN}	0 V ≤V _{II}	_N ≤LV _{DD}	—	±10	μA

8.2 GMII, MII, RMII, TBI, RGMII, and RTBI AC Timing Specifications

The AC timing specifications for GMII, MII, TBI, RGMII, and RTBI are presented in this section.

8.2.1 GMII Timing Specifications

This sections describe the GMII transmit and receive AC timing specifications.



8.3.2 MII Management AC Electrical Specifications

This table provides the MII management AC timing specifications.

Table 37. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD} is 3.3 V ± 10%.

Parameter/Condition	Symbol ¹	Min	Тур	Мах	Unit	Notes
MDC frequency	f _{MDC}	—	2.5	—	MHz	2
MDC period	t _{MDC}	—	400	—	ns	—
MDC clock pulse width high	t _{MDCH}	32	—	—	ns	_
MDC to MDIO delay	^t мрткнрх ^t мрткнрv	10 —	_	 110	ns	3
MDIO to MDC setup time	t _{MDRDVKH}	10	—	—	ns	—
MDIO to MDC hold time	t _{MDRDXKH}	0	—	—	ns	—
MDC rise time	t _{MDCR}	—	—	10	ns	—
MDC fall time	t _{MDHF}	_	_	10	ns	

Notes:

- The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDRDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
 </sub>
- This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a csb_clk of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz).
- 3. This parameter is dependent on the ce_clk speed (that is, for a ce_clk of 200 MHz, the delay is 90 ns and for a ce_clk of 300 MHz, the delay is 63 ns).

This figure shows the MII management AC timing diagram.



Figure 21. MII Management Interface Timing Diagram





Figure 27. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4 (DLL Bypass Mode)

PCI AC Electrical Specifications

Table 47. PCI AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol ¹	Min	Мах	Unit	Notes
Clock to output high impedance	t _{PCKHOZ}	_	14	ns	2, 3
Input setup to clock	t _{PCIVKH}	3.0	_	ns	2, 4
Input hold from clock	t _{PCIXKH}	0.3	_	ns	2, 4, 6

Notes:

- The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
 </sub>
- 2. See the timing measurement conditions in the PCI 2.2 Local Bus Specifications.
- 3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 4. Input timings are measured at the pin.
- 5. In rev. 2.0 silicon, due to errata, t_{PCIHOV} maximum is 6.6 ns. Refer to Errata PCI21 in Chip Errata for the MPC8360E, Rev. 1.
- 6. In rev. 2.0 silicon, due to errata, t_{PCIXKH} minimum is 1 ns. Refer to Errata PCI17 in Chip Errata for the MPC8360E, Rev. 1.

Table 48. PCI AC Timing Specifications at 33 MHz

Parameter	Symbol ¹	Min	Max	Unit	Notes
Clock to output valid	t _{PCKHOV}	_	11	ns	2
Output hold from clock	t _{PCKHOX}	2	-	ns	2
Clock to output high impedance	t _{PCKHOZ}	_	14	ns	2, 3
Input setup to clock	t _{PCIVKH}	7.0	_	ns	2, 2
Input hold from clock	t _{PCIXKH}	0.3	_	ns	2, 4, 5

Notes:

- The symbols used for timing specifications herein follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
- 2. See the timing measurement conditions in the PCI 2.2 Local Bus Specifications.
- 3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 4. Input timings are measured at the pin.
- 5. In rev. 2.0 silicon, due to errata, t_{PCIXKH} minimum is 1 ns. Refer to Errata PCI17 in Chip Errata for the MPC8360E, Rev. 1.

This figure provides the AC test load for PCI.



Figure 36. PCI AC Test Load



SPI AC Timing Specifications

Table 56.	SPI AC	Timing	Specifications ¹
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Characteristic	Symbol ²	Min	Мах	Unit
SPI inputs—Slave mode (external clock) input hold time	t _{NEIXKH}	2	—	ns

Notes:

- 1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
- The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state)</sub> for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

This figure provides the AC test load for the SPI.



Figure 41. SPI AC Test Load

These figures represent the AC timing from Table 56. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

This figure shows the SPI timing in slave mode (external clock).



Note: The clock edge is selectable on SPI.

Figure 42. SPI AC Timing in Slave Mode (External Clock) Diagram

This figure shows the SPI timing in Master mode (internal clock).







This figure shows the TDM/SI timing with external clock.



Note: The clock edge is selectable on TDM/SI



17.3 UTOPIA/POS

This section describes the DC and AC electrical specifications for the UTOPIA/POS of the MPC8360E/58E.

17.4 UTOPIA/POS DC Electrical Characteristics

This table provides the DC electrical characteristics for the device UTOPIA.

 Table 59. UTOPIA DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Мах	Unit
Output high voltage	V _{OH}	I _{OH} = -8.0 mA	2.4	_	V
Output low voltage	V _{OL}	I _{OL} = 8.0 mA	—	0.5	V
Input high voltage	V _{IH}	—	2.0	OV _{DD} + 0.3	V
Input low voltage	V _{IL}	—	-0.3	0.8	V
Input current	I _{IN}	$0 V \leq V_{IN} \leq OV_{DD}$	—	±10	μA

17.5 UTOPIA/POS AC Timing Specifications

This table provides the UTOPIA input and output AC timing specifications.

Table 60. UTOPIA AC Timing Specifications¹

Characteristic	Symbol ²	Min	Мах	Unit	Notes
UTOPIA outputs—Internal clock delay	t _{UIKHOV}	0	11.5	ns	_
UTOPIA outputs—External clock delay	t _{UEKHOV}	1	11.6	ns	_
UTOPIA outputs—Internal clock high impedance	t _{UIKHOX}	0	8.0	ns	—
UTOPIA outputs—External clock high impedance	t _{UEKHOX}	1	10.0	ns	_
UTOPIA inputs—Internal clock input setup time	t _{UIIVKH}	6	—	ns	—
UTOPIA inputs—External clock input setup time	t _{UEIVKH}	4	—	ns	3



18.3 AC Test Load

These figures represent the AC timing from Table 62 and Table 63. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

This figure shows the timing with external clock.



Figure 50. AC Timing (External Clock) Diagram

This figure shows the timing with internal clock.



Figure 51. AC Timing (Internal Clock) Diagram



20 Package and Pin Listings

This section details package parameters, pin assignments, and dimensions. The MPC8360E/58E is available in a tape ball grid array (TBGA), see Section 20.1, "Package Parameters for the TBGA Package," and Section 20.2, "Mechanical Dimensions of the TBGA Package," for information on the package.

20.1 Package Parameters for the TBGA Package

The package parameters for rev. 2.0 silicon are as provided in the following list. The package type is $37.5 \text{ mm} \times 37.5 \text{ mm}$, 740 tape ball grid array (TBGA).

Package outline	$37.5 \text{ mm} \times 37.5 \text{ mm}$
Interconnects	740
Pitch	1.00 mm
Module height (typical)	1.46 mm
Solder Balls	62 Sn/36 Pb/2 Ag (ZU package)
	95.5 Sn/0.5 Cu/4Ag (VV package)
Ball diameter (typical)	0.64 mm



Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
IRQ[4:5]	G33, G32	I/O	OV _{DD}	—
IRQ[6]/LCS[6]/CKSTOP_OUT	E35	I/O	OV _{DD}	—
IRQ[7]/LCS[7]/CKSTOP_IN	H36	I/O	OV _{DD}	—
	DUART			
UART1_SOUT/M1SRCID[0]/ M2SRCID[0]/LSRCID[0]	E32	0	OV _{DD}	_
UART1_SIN/M1SRCID[1]/ M2SRCID[1]/LSRCID[1]	B34	I/O	OV _{DD}	
UART1_CTS/M1SRCID[2]/ M2SRCID[2]/LSRCID[2]	C34	I/O	OV _{DD}	
UART1_RTS/M1SRCID[3]/ M2SRCID[3]/LSRCID[3]	A35	0	OV _{DD}	_
	I ² C Interface			<u></u>
IIC1_SDA	D34	I/O	OV _{DD}	2
IIC1_SCL	B35	I/O	OV _{DD}	2
IIC2_SDA	E33	I/O	OV _{DD}	2
IIC2_SCL	C35	I/O	OV _{DD}	2
QUICC Engine				
CE_PA[0]	F8	I/O	LV _{DD0}	—
CE_PA[1:2]	AH1, AG5	I/O	OV _{DD}	—
CE_PA[3:7]	F6, D4, C3, E5, A3	I/O	LV _{DD} 0	—
CE_PA[8]	AG3	I/O	OV _{DD}	—
CE_PA[9:12]	F7, B3, E6, B4	I/O	LV _{DD} 0	—
CE_PA[13:14]	AG1, AF6	I/O	OV _{DD}	—
CE_PA[15]	B2	I/O	LV _{DD} 0	—
CE_PA[16]	AF4	I/O	OV _{DD}	—
CE_PA[17:21]	B16, A16, E17, A17, B17	I/O	LV _{DD} 1	—
CE_PA[22]	AF3	I/O	OV _{DD}	—
CE_PA[23:26]	C18, D18, E18, A18	I/O	LV _{DD} 1	—
CE_PA[27:28]	AF2, AE6	I/O	OV _{DD}	—
CE_PA[29]	B19	I/O	LV _{DD} 1	—
CE_PA[30]	AE5	I/O	OV_{DD}	—
CE_PA[31]	F16	I/O	LV _{DD} 1	—



Pinout Listings

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LV _{DD} 1	C17, D16	Power for UCC2 Ethernet interface option 1 (2.5 V, 3.3 V)	LV _{DD} 1	9
LV _{DD} 2	B18, E21	Power for UCC2 Ethernet interface option 2 (2.5 V, 3.3 V)	LV _{DD} 2	9
V _{DD}	C36, D29, D35, E16, F9, F12, F15, F17, F18, F20, F21, F23, F25, F26, F29, F31, F32, F33, G6, J6, K32, M32, N6, P33, R6, R32, U32, V6, Y5, Y32, AB6, AB33, AD6, AF32, AK6, AL6, AM7, AM9, AM10, AM11, AM12, AM13, AM14, AM15, AM18, AM21, AM25, AM28, AM32, AN15, AN21, AN26, AU9, AU17	Power for core (1.2 V)	V _{DD}	_
OV _{DD}	A10, B9, B15, B32, C1, C12, C22, C29, D24, E3, E10, E27, G4, H35, J1, J35, K2, M4, N3, N34, R2, R37, T36, U2, U33, V4, V34, W3, Y35, Y37, AA1, AA36, AB2, AB34	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	
MVREF1	AN20	I	DDR reference voltage	_
MVREF2	AU32	I	DDR reference voltage	_
			Г	
SPARE1	B11	I/O	OV _{DD}	8
SPARE3	AH32	—	GV _{DD}	8
SPARE4	AU18		GV _{DD}	7
SPARE5	AP1	—	GV _{DD}	8

Table 67. MPC8358E TBGA Pinout Listing (continued)



Table 67. MPC8358E TBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
No Connect				
NC	AM16, AM17, AM20, AN13, AN16, AN17, AP10, AP11, AP13, AP15, AP18, AR11, AR13, AR14, AR15, AR16, AR17, AR20, AT11, AT12, AT13, AT14, AT16, AT17, AT18, AU10, AU11, AU12, AU13, AU15, AU19	_	_	

Notes:

- 1. This pin is an open drain signal. A weak pull-up resistor (1 k Ω) should be placed on this pin to OV_{DD}.
- 2. This pin is an open drain signal. A weak pull-up resistor (2–10 k Ω) should be placed on this pin to OV_{DD} .
- 3. This output is actively driven during reset rather than being three-stated during reset.
- 4. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
- 5. This pin should have a weak pull up if the chip is in PCI host mode. Follow PCI specifications recommendation.
- 6. These are On Die Termination pins, used to control DDR2 memories internal termination resistance.
- 7. This pin must always be tied to GND.
- 8. This pin must always be left not connected.
- 9. Refer to MPC8360E PowerQUICC II Pro Integrated Communications Processor Reference Manual section on "RGMII Pins," for information about the two UCC2 Ethernet interface options.
- 10. This pin must always be tied to GV_{DD} .
- 11. It is recommended that MDIC0 be tied to GND using an 18.2 Ω resistor and MDIC1 be tied to DDR power using an 18.2 Ω resistor for DDR2.



This figure shows the internal distribution of clocks within the MPC8358E.





The primary clock source for the device can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. Note that in PCI host mode, the primary clock input also depends on whether PCI clock outputs are selected with RCWH[PCICKDRV]. When the device is configured as a PCI host device (RCWH[PCIHOST] = 1) and PCI clock output is selected (RCWH[PCICKDRV] = 1), CLKIN is its primary input clock. CLKIN feeds the PCI clock divider (\div 2) and the multiplexors for PCI_SYNC_OUT and PCI_CLK_OUT. The CFG_CLKIN_DIV configuration input selects whether CLKIN or CLKIN/2 is driven out on the PCI_SYNC_OUT signal. The OCCR[PCIOEN*n*] parameters enable the PCI_CLK_OUT*n*, respectively.

PCI_SYNC_OUT is connected externally to PCI_SYNC_IN to allow the internal clock subsystem to synchronize to the system PCI clocks. PCI_SYNC_OUT must be connected properly to PCI_SYNC_IN, with equal delay to all PCI agent devices in the system, to allow the device to function. When the device is configured as a PCI agent device, PCI_CLK is the primary input





ordered, see Section 24.1, "Part Numbers Fully Addressed by this Document," for part ordering details and contact your Freescale sales representative or authorized distributor for more information.

Characteristic ¹	400 MHz	533 MHz	667 MHz ²	Unit
e300 core frequency (<i>core_clk</i>)	266–400	266–533	266–667	MHz
Coherent system bus frequency (<i>csb_clk</i>)	133–333			MHz
QUICC Engine frequency ³ (<i>ce_clk</i>)	266–500			MHz
DDR and DDR2 memory bus frequency (MCLK) ⁴	100–166.67		MHz	
Local bus frequency (LCLK <i>n</i>) ⁵	16.67–133		MHz	
PCI input frequency (CLKIN or PCI_CLK)	25–66.67			MHz
Security core maximum internal operating frequency	133	133	166	MHz

Table 69. Operating Frequencies for the TBGA Package

Notes:

- 1. The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen such that the resulting *csb_clk*, MCLK, LCLK[0:2], and *core_clk* frequencies do not exceed their respective maximum or minimum operating frequencies.
- 2. The 667 MHz core frequency is based on a 1.3 V V_{DD} supply voltage.
- 3. The 500 MHz QE frequency is based on a 1.3 V V_{DD} supply voltage.
- 4. The DDR data rate is 2x the DDR memory bus frequency.
- 5. The local bus frequency is 1/2, 1/4, or 1/8 of the *lb_clk* frequency (depending on LCRR[CLKDIV]) which is in turn 1× or 2× the *csb_clk* frequency (depending on RCWL[LBCM]).

21.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] and RCWL[SVCOD] parameters. This table shows the multiplication factor encodings for the system PLL.

RCWL[SPMF]	System PLL Multiplication Factor	
0000	× 16	
0001	Reserved	
0010	× 2	
0011	× 3	
0100	× 4	
0101	× 5	
0110	× 6	
0111	× 7	
1000	× 8	
1001	× 9	
1010	× 10	
1011	× 11	

Table 70. System PLL Multiplication Factors



22.3.1 Experimental Determination of the Junction Temperature with a Heat Sink

When heat sink is used, the junction temperature is determined from a thermocouple inserted at the interface between the case of the package and the interface material. A clearance slot or hole is normally required in the heat sink. Minimizing the size of the clearance is important to minimize the change in thermal performance caused by removing part of the thermal interface to the heat sink. Because of the experimental difficulties with this technique, many engineers measure the heat sink temperature and then back calculate the case temperature using a separate measurement of the thermal resistance of the interface. From this case temperature, the junction temperature is determined from the junction-to-case thermal resistance.

$$T_J = T_C + (R_{\theta JC} \times P_D)$$

where:

 T_I = junction temperature (° C)

 T_C = case temperature of the package (° C)

 $R_{\theta JC}$ = junction to case thermal resistance (° C/W)

 P_D = power dissipation (W)

23 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8360E/58E. Additional information can be found in *MPC8360E/MPC8358E PowerQUICC Design Checklist* (AN3097).

23.1 System Clocking

The device includes two PLLs, as follows.

- The platform PLL (AV_{DD}1) generates the platform clock from the externally supplied CLKIN input. The frequency ratio between the platform and CLKIN is selected using the platform PLL ratio configuration bits as described in Section 21.1, "System PLL Configuration."
- The e300 core PLL (AV_{DD}2) generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in Section 21.2, "Core PLL Configuration."

23.2 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD} 1, AV_{DD} 2, respectively). The AV_{DD} level should always be equivalent to V_{DD} , and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide five independent filter circuits as illustrated in Figure 56, one to each of the five AV_{DD} pins. By providing independent filters to each PLL, the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of package, without the inductance of vias.



This figure shows the PLL power supply filter circuit.



Figure 56. PLL Power Supply Filter Circuit

23.3 Decoupling Recommendations

Due to large address and data buses as well as high operating frequencies, the device can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the device system, and the device itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each V_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} pins of the device. These decoupling capacitors should receive their power from separate V_{DD} , OV_{DD} , GV_{DD} , and GND power planes in the PCB, utilizing short traces to minimize inductance. Capacitors may be placed directly under the device using a standard escape pattern. Others may surround the part.

These capacitors should have a value of 0.01 or 0.1 μ F. Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0603 sizes.

Additionally, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD} , OV_{DD} , GV_{DD} , GV_{DD} , and LV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors—100–330 μ F (AVX TPS tantalum or Sanyo OSCON).

23.4 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. Unused active low inputs should be tied to OV_{DD} , GV_{DD} , or LV_{DD} as required. Unused active high inputs should be connected to GND. All NC (no-connect) signals must remain unconnected.

Power and ground connections must be made to all external V_{DD}, GV_{DD}, LV_{DD}, OV_{DD}, and GND pins of the device.

23.5 Output Buffer DC Impedance

The device drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I^2C).

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $OV_{DD}/2$ (see Figure 57). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and R_p is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_p then becomes the resistance of the pull-up devices. R_p and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

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Asia/Pacific:

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